

## Supporting Information

# Flexible Paper-Based Ag Dendritic SERS Chips for Rapid In-Situ Detection of Thiram Residues on Pear Skin

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### Calculation of limit of detection (LOD)

The standard curve of linear detecting range was given as:

$$Y = A + B \times \text{Log}(X) \quad (1)$$

where A and B are intercept and slope of regression equation obtained through the plot of the logarithmic SERS intensity (Y) – logarithmic concentration (X).

The LOD is calculated using the following equation<sup>1</sup>:

$$\text{LOD} = 10^{[(Y_{\text{blank}} + 3SD)/Y_{\text{blank}} - A]/B} \quad (2)$$

where  $Y_{\text{blank}}$  and SD are the SERS signal and the standard deviation of blank sample, respectively.

SD is calculated via the well-known formula:

$$SD = \sqrt{\frac{1}{n-1} \times \sum_i^n (x_i - x_{\text{average}})^2} \quad (3)$$

where  $x_i$  if the “i” sample of the series of measurements,  $x_{\text{average}}$  is the average value of SERS signal obtained from the blank sample repeated n times.

### Calculation of enhancement factor (EF)

The EF value is calculated according to the well-established equation, which was employed in several published studies<sup>2,3</sup>:

$$EF = \frac{I_{\text{SERS}}}{I_{\text{Raman}}} \times \frac{N_{\text{bulk}}}{N_{\text{surface}}} \quad (4)$$

Where  $I_{Raman}$  is the Raman signal intensity of the  $1380\text{ cm}^{-1}$  peak of the thiram analyte collected directly from the powder sample (the result is presented in Figure S1);  $I_{SERS}$  is the SERS intensity of the  $1386\text{ cm}^{-1}$  peak of thiram on the Paper/Ag-d SERS chips; and  $N_{bulk}$  is the number of analyte molecules that are probed on the Raman spectrum of thiram powder, while  $N_{surface}$  is the number of analyte molecules probed using SERS.

$N_{bulk}$  can be calculated following:

$$N_{bulk} = \frac{A_{laser} \times h \times \rho}{M} \times N_A$$

(5)

where  $A_{laser}$ ,  $h$ ,  $\rho$  and  $m$  are the laser spot area, the focal length, the density of the solid analyte and its molecular weight, respectively; and  $N_A$  is the Avogadro number.

$N_{surface}$  can be expressed as:

$$N_{surface} = \frac{C \times V}{A_{substrate}} \times N_A \times A_{laser} \quad (6)$$

where  $C$ ,  $V$ ,  $A_{substrate}$  are the concentration, the volume drop-casted of the analyte, and the area of the substrate, respectively;  $N_A$  is the Avogadro number; and  $A_{laser}$  is the laser spot area.

Thus EF can be calculated as:

$$EF = \frac{I_{SERS}}{I_{Raman}} \times \frac{N_{bulk}}{N_{surface}} = \frac{I_{SERS}}{I_{Raman}} \times \frac{h \times \rho \times A_{substrate}}{M \times C \times V}$$

(7)

In our case,  $I_{Raman}$  value is derived from the intensity of the peak at  $1380\text{ cm}^{-1}$  in the Raman spectrum of thiram in its powdered form,  $I_{SERS}$  value is obtained from the intensity of the peak at

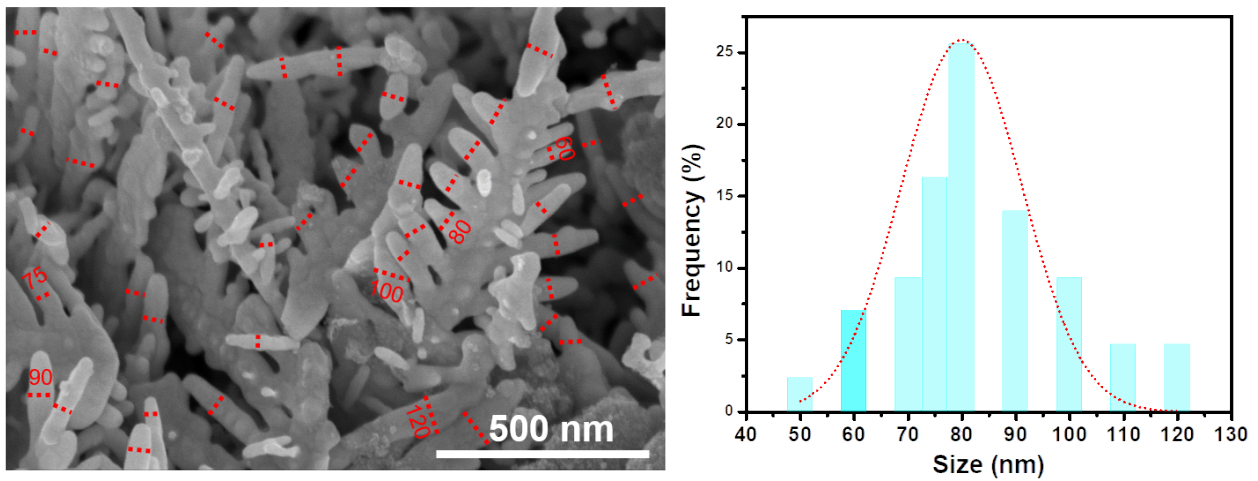
1386  $\text{cm}^{-1}$  in the SERS spectrum of thiram at a concentration of  $10^{-10}$  M,  $h = 2 \mu\text{m}$ ,  $\rho_{\text{thiram}} = 1.29 \text{ g/cm}^3$ ;  $M_{\text{thiram}} = 240 \text{ g/mol}$ ;  $A_{\text{substrate}} = 4 \text{ mm}^2$ ,  $V = 2 \mu\text{L}$ .

### Calculation of relative standard deviation (RSD)

The RSD value of repeatability and reproducibility is calculated via the well-known formula:

$$\text{RSD} = \frac{SD \times 100}{x_{\text{average}}} \quad (8)$$

where SD is the standard deviation that calculates using equation 4 and  $x_{\text{average}}$  is the average value of SERS signal obtained from each measurement.



**Figure S1. FE-SEM images of flexible Paper/Ag-d chips at high resolution and the size distribution of Ag branches.**

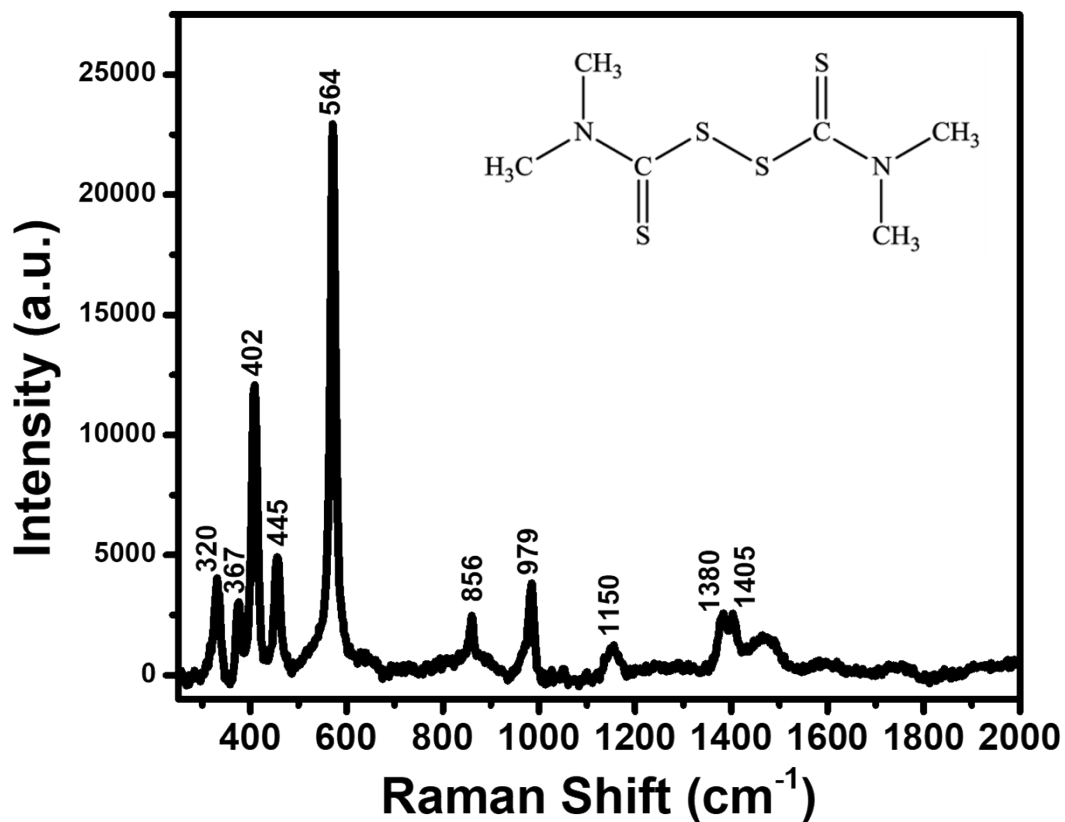


Figure S2. Raman spectrum of pure thiram powder and its molecular structure.

Table S1. Assignments of vibrational bands in Raman and SERS spectra of thiram.

Raman peak (cm <sup>-1</sup> )	SERS peak (cm <sup>-1</sup> )	Peak assignment
320		$\delta(\text{S}=\text{CS}), \delta(\text{CSS})$ <sup>4,5</sup>
367		$\nu(\text{CH}_3\text{CN})$ <sup>4</sup> , $\nu(\text{CS})$ <sup>4</sup>
402		$\nu_s(\text{CSS}), \nu(\text{C}=\text{S})$ <sup>4-6</sup>
445	446	$\nu_s(\text{CSS})$ <sup>4</sup> , $\delta(\text{C}-\text{N}-\text{C})$ <sup>5</sup>
564	560	$\nu(\text{S}-\text{S}) + \nu_s(\text{CSS})$ <sup>4-6</sup>
856	860	$\nu_{\text{as}}(\text{CH}_3-\text{N})$ <sup>4,6</sup>

979		$\nu_{\text{as}}(\text{CSS})$ <sup>4,6</sup>
1150	1150	$\rho(\text{CH}_3) + \nu(\text{N-CH}_3)$ <sup>5-7</sup>
1380	1386	$\delta(\text{CH}_3), \nu(\text{C-N})$ <sup>4,6</sup>

$\delta$  = bending;  $\rho$  = rocking;  $\nu_s$  = symmetric stretching;  $\nu_{\text{as}}$  = antisymmetric stretching.

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